#### **IEEE/IEC Dual Logo Agreement**

DASC-SC Meeting San Diego, CA 11 June 2004



# Purpose of IEEE/IEC Dual-Logo Agreement

- Avoid duplication of efforts
- Recognition of contribution
- Intellectual Property rights
- Develop maintenance procedures



## **Highlights**

- Approved IEEE Standards are eligible for submission
- Documents Submitted to the IEC Standardization Management Board (SMB) for consideration
- The appropriate IEC TC reviews the document (FDIS ballot). No revisions can be made.
- Both organizations agree on the designation
- Process takes about six months



#### **Identifying Dual Logo Candidates**

- Candidates may be suggested by an IEEE Sponsor Chair, IEEE Working Group Chair, IEC Technical Committee or the IEC Central Office.
- Appropriate Parties are contacted
  - IEEE Working Group Chair
  - IEEE Sponsor Chair
  - US TAG (if one exists)
  - Chair/Secretary of relevant IEC TC



### **Example of a Dual-Logo Standard**

INTERNATIONAL STANDARD IEC 60488-2

First editio

**IEEE 488.2** 

Standard digital interface for programmable instrumentation –

Part 2: Codes, formats, protocols and common commands



Reference number ISC 65498-2(E):2004 ISES Std. 489-2(E):1862



## **Additional processes**

 Revision/Maintenance Procedures developed and approved by IEC and IEEE

 Reaffirmation/Reconfirmation procedures under development



## Why do this?

- Sends a strong and clear message to industry that the major technical standards developing organizations aim to cooperate toward one standard in the world wherever possible
- From a market and trade perspective, symbolizes a loosening of real and perceived barriers.



## Approved IEC/IEEE Dual Logo Standards

- IEEE Std 1076™-2002, IEEE Standard VHDL Language Reference Manual
- IEEE Std 1076.4™-2000, IEEE Standard VITAL ASIC (Application Specific Integrated Circuit) Modeling Specification
- IEEE Std 1364™-2001, IEEE Standard Verilog Hardware Description Language
- IEEE Std 1497™-2001, IEEE Standard for Standard Delay Format (SDF) for the Electronic Design Process



## Future Submissions (Confirmed)

- IEEE Std 1232™-2002, IEEE Standard for Artificial Intelligence Exchange and Service Tie to All Test Environments (AI- ESTATE)
- IEEE Std 1603™-2003, IEEE Standard for an Advanced Library Format (ALF) Describing Integrated Circuit (IC) Technology, Cells, and Blocks



#### **Potential Submissions**

- IEEE Std 1076.1™-1999, IEEE
   Standard VHDL Analog and Mixed-Signal Extensions
- IEEE Std 1076.6™-2004, Standard for VHDL Register Transfer Level (RTL) Synthesis
- IEEE Std 1364.1™-2002, IEEE
  Standard for Verilog Register
  Transfer Level Synthesis

